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April 1st, 2010 Renesas Electronics Corporation

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R1LP0408C-C Series

4M SRAM (512-kword \times 8-bit)

REJ03C0077-0200Z Rev. 2.00 May.26.2004

Description

The R1LP0408C-C is a 4-Mbit static RAM organized 512-kword × 8-bit. R1LP0408C-C Series has realized higher density, higher performance and low power consumption by employing CMOS process technology (6-transistor memory cell). The R1LP0408C-C Series offers low power standby power dissipation; therefore, it is suitable for battery backup systems. It has packaged in 32-pin SOP, 32-pin TSOP II.

Features

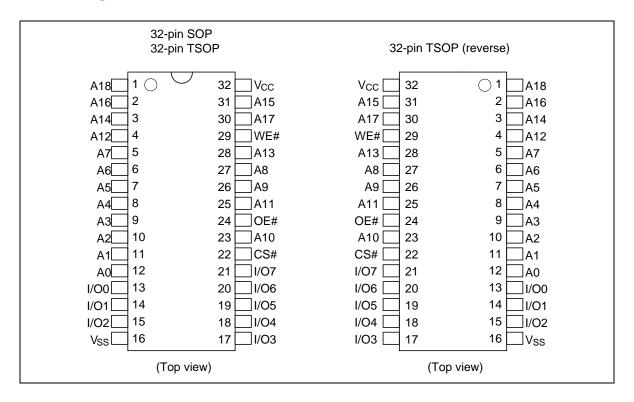
- Single 5 V supply: 5 V ± 10%
 Access time: 55/70 ns (max)
- Power dissipation:
 - Active: 10 mW/MHz (typ)
 - Standby: 4 μW (typ)
- Completely static memory.
 - No clock or timing strobe required
- Equal access and cycle times
- Common data input and output.
 - Three state output
- Directly TTL compatible.
 - All inputs and outputs
- Battery backup operation.
- Operating temperature: $-20 \text{ to } +70^{\circ}\text{C}$

R1LP0408C-C Series

Ordering Information

| Type No. | Access time | Package |
|-----------------|-------------|--|
| R1LP0408CSP-5SC | 55 ns | 525-mil 32-pin plastic SOP (32P2M-A) |
| R1LP0408CSP-7LC | 70 ns | |
| R1LP0408CSB-5SC | 55 ns | 400-mil 32-pin plastic TSOP II (32P3Y-H) |
| R1LP0408CSB-7LC | 70 ns | |
| R1LP0408CSC-5SC | 55 ns | 400-mil 32-pin plastic TSOP II reverse (32P3Y-J) |
| R1LP0408CSC-7LC | 70 ns | |

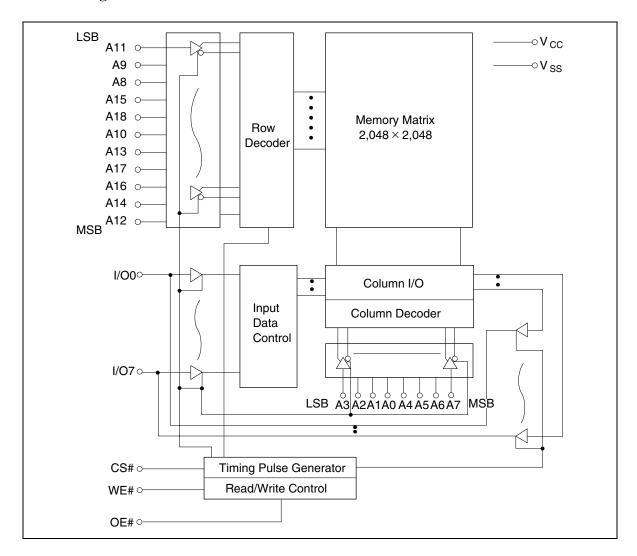
Pin Arrangement



Pin Description

| Pin name | Function |
|-----------------|-------------------|
| A0 to A18 | Address input |
| I/O0 to I/O7 | Data input/output |
| CS# (CS) | Chip select |
| OE# (OE) | Output enable |
| WE# (WE) | Write enable |
| V _{CC} | Power supply |
| V _{SS} | Ground |

Block Diagram



Operation Table

| WE# | CS# | OE# | Mode | V _{CC} current | I/00 to I/07 | Ref. cycle |
|-----|-----|-----|----------------|------------------------------------|--------------|-----------------|
| × | Н | × | Not selected | I _{SB} , I _{SB1} | High-Z | _ |
| Н | L | Н | Output disable | I _{CC} | High-Z | _ |
| Н | L | L | Read | I _{CC} | Dout | Read cycle |
| L | L | Н | Write | I _{CC} | Din | Write cycle (1) |
| L | L | L | Write | I _{CC} | Din | Write cycle (2) |

Note: H: V_{IH}, L: V_{IL}, ×: V_{IH} or V_{IL}

Absolute Maximum Ratings

| Parameter | Symbol | Value | Unit |
|---|-----------------|------------------------------------|------|
| Power supply voltage relative to V _{SS} | V _{CC} | -0.5 to +7.0 | V |
| Terminal voltage on any pin relative to V _{SS} | V _T | -0.5^{*1} to $V_{CC} + 0.3^{*2}$ | V |
| Power dissipation | P _T | 0.7 | W |
| Operating temperature | Topr | –20 to +70 | °C |
| Storage temperature range | Tstg | -65 to +150 | °C |
| Storage temperature range under bias | Tbias | -20 to +85 | °C |

Notes: 1. V_T min: -3.0 V for pulse half-width ≤ 30 ns.

2. Maximum voltage is +7.0 V.

DC Operating Conditions

 $(Ta = -20 \text{ to } +70^{\circ}\text{C})$

| Parameter | Symbol | Min | Тур | Max | Unit |
|--------------------|-----------------|--------------------|-----|-----------------------|------|
| Supply voltage | V _{CC} | 4.5 | 5.0 | 5.5 | V |
| | V_{SS} | 0 | 0 | 0 | V |
| Input high voltage | V _{IH} | 2.2 | _ | V _{CC} + 0.3 | V |
| Input low voltage | V _{IL} | -0.3* ¹ | _ | 0.8 | V |

Note: 1. V_{IL} min: -3.0 V for pulse half-width ≤ 30 ns.

DC Characteristics

| Parameter | | | Symbol | Min | Тур | Max | Unit | Test conditions |
|---------------------------|--------------------|----------|------------------|-----|-------------------|-----|------|--|
| Input leakage cur | rent | | I _{LI} | _ | _ | 1 | μΑ | $Vin = V_{SS}$ to V_{CC} |
| Output leakage c | urrent | | I _{LO} | _ | _ | 1 | μΑ | $CS\# = V_{IH}$ or $OE\# = V_{IH}$ or $WE\# = V_{IL}$ or $V_{I/O} = V_{SS}$ to V_{CC} |
| Operating curren | t | | I _{CC} | | 1.5* ¹ | 3 | mA | $\begin{split} \text{CS\#} &= \text{V}_{\text{IL}}, \\ \text{Others} &= \text{V}_{\text{IH}}/\text{V}_{\text{IL}}, \text{I}_{\text{I/O}} = 0 \text{ mA} \end{split}$ |
| Average operating current | | | I _{CC1} | _ | 8* ¹ | 25 | mA | Min. cycle, duty = 100%, $CS\# = V_{IL}$, Others = V_{IH}/V_{IL} $I_{I/O} = 0$ mA |
| | | | I _{CC2} | _ | 2* ¹ | 5 | mA | Cycle time = 1 μ s, duty = 100%, $I_{I/O}$ = 0 mA, CS# \leq 0.2 V, $V_{IH} \geq V_{CC} - 0.2$ V, $V_{IL} \leq$ 0.2 V |
| Standby current | | | I _{SB} | _ | 0.1* ¹ | 0.5 | mA | CS# = V _{IH} |
| Standby current | -5SC | to +70°C | I _{SB1} | _ | _ | 8 | μΑ | $Vin \geq 0 \text{ V, CS\#} \geq V_{CC} - 0.2 \text{ V}$ |
| | | to +40°C | I _{SB1} | _ | 1.0*2 | 3 | μΑ | - |
| | | to +25°C | I _{SB1} | _ | 0.8*1 | 3 | μΑ | - |
| | -7LC | to +70°C | I _{SB1} | _ | _ | 16 | μΑ | |
| | | to +40°C | I _{SB1} | _ | 1.0*2 | 10 | μΑ | |
| | | to +25°C | I _{SB1} | _ | 0.8*1 | 10 | μΑ | - |
| Output low voltage | Output low voltage | | V _{OL} | _ | _ | 0.4 | V | I _{OL} = 2.1 mA |
| Output high volta | ge | | V _{OH} | 2.4 | _ | | V | $I_{OH} = -1.0 \text{ mA}$ |
| | | | V_{OH2} | 2.6 | | | V | $I_{OH} = -0.1 \text{ mA}$ |

Notes: 1. Typical values are at $V_{CC} = 5.0 \text{ V}$, $Ta = +25^{\circ}\text{C}$ and specified loading, and not guaranteed.

2. Typical values are at V_{CC} = 5.0 V, Ta = +40°C and specified loading, and not guaranteed.

Capacitance

 $(Ta = +25^{\circ}C, f = 1.0 \text{ MHz})$

| Parameter | Symbol | Min | Тур | Max | Unit | Test conditions | Note |
|--------------------------|------------------|-----|-----|-----|------|------------------------|------|
| Input capacitance | Cin | _ | _ | 8 | pF | Vin = 0 V | 1 |
| Input/output capacitance | C _{I/O} | _ | _ | 10 | pF | V _{I/O} = 0 V | 1 |

Note: 1. This parameter is sampled and not 100% tested.

AC Characteristics

(Ta = -20 to +70 °C, V_{CC} = 5 V \pm 10%, unless otherwise noted.)

Test Conditions

• Input pulse levels: $V_{IL} = 0.4 \text{ V}$, $V_{IH} = 2.4 \text{ V}$

• Input rise and fall time: 5 ns

• Input and output timing reference levels: 1.5 V

• Output load: $1 \text{ TTL Gate} + C_L (50 \text{ pF}) (R1LP0408C-5SC)$

1 TTL Gate + C_L (100 pF) (R1LP0408C-7LC)

(Including scope and jig)

Read Cycle

R1LP0408C-C

| | | -5SC | | -7LC | | _ | |
|------------------------------------|------------------|------|-----|------|-----|------|-------|
| Parameter | Symbol | Min | Max | Min | Max | Unit | Notes |
| Read cycle time | t _{RC} | 55 | _ | 70 | _ | ns | |
| Address access time | t _{AA} | _ | 55 | | 70 | ns | |
| Chip select access time | t _{CO} | _ | 55 | | 70 | ns | |
| Output enable to output valid | t _{OE} | | 25 | | 35 | ns | |
| Chip select to output in low-Z | t _{LZ} | 10 | _ | 10 | _ | ns | 2 |
| Output enable to output in low-Z | t _{OLZ} | 5 | _ | 5 | _ | ns | 2 |
| Chip deselect to output in high-Z | t _{HZ} | 0 | 20 | 0 | 25 | ns | 1, 2 |
| Output disable to output in high-Z | t _{OHZ} | 0 | 20 | 0 | 25 | ns | 1, 2 |
| Output hold from address change | t _{OH} | 10 | _ | 10 | | ns | |

Write Cycle

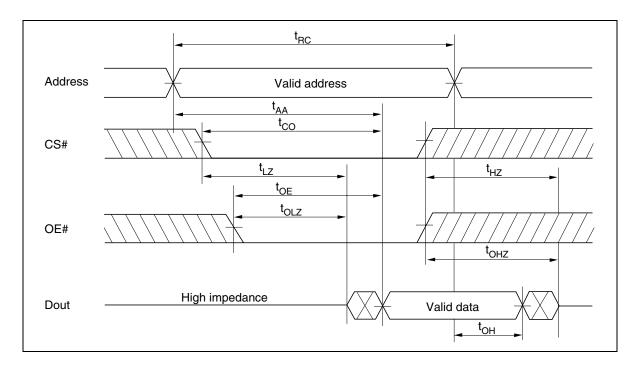
R1LP0408C-C

| | | -5SC | | -7LC | | | |
|------------------------------------|------------------|------|-----|------|-----|------|---------|
| Parameter | Symbol | Min | Max | Min | Max | Unit | Notes |
| Write cycle time | t_{WC} | 55 | _ | 70 | _ | ns | |
| Chip selection to end of write | t _{CW} | 50 | _ | 60 | _ | ns | 4 |
| Address setup time | t _{AS} | 0 | _ | 0 | | ns | 5 |
| Address valid to end of write | t _{AW} | 50 | _ | 60 | _ | ns | |
| Write pulse width | t _{WP} | 40 | _ | 50 | _ | ns | 3, 12 |
| Write recovery time | t _{WR} | 0 | _ | 0 | _ | ns | 6 |
| Write to output in high-Z | t_{WHZ} | 0 | 20 | 0 | 25 | ns | 1, 2, 7 |
| Data to write time overlap | t_{DW} | 25 | _ | 30 | _ | ns | |
| Data hold from write time | t _{DH} | 0 | _ | 0 | _ | ns | |
| Output active from end of write | t _{OW} | 5 | _ | 5 | _ | ns | 2 |
| Output disable to output in high-Z | t _{OHZ} | 0 | 20 | 0 | 25 | ns | 1, 2, 7 |

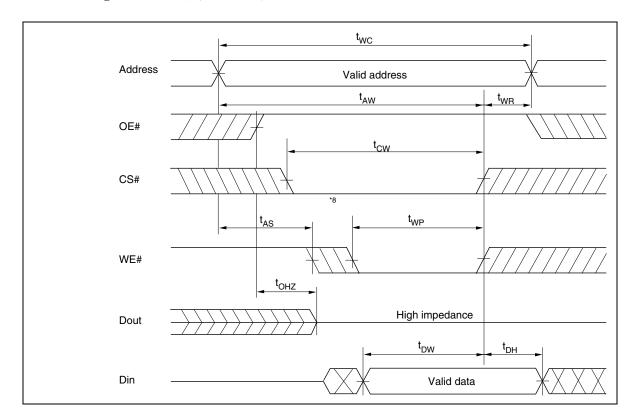
- Notes: 1. t_{HZ} , t_{OHZ} and t_{WHZ} are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.
 - 2. This parameter is sampled and not 100% tested.
 - 3. A write occurs during the overlap (t_{WP}) of a low CS# and a low WE#. A write begins at the later transition of CS# going low or WE# going low. A write ends at the earlier transition of CS# going high or WE# going high. t_{WP} is measured from the beginning of write to the end of write.
 - 4. t_{CW} is measured from CS# going low to the end of write.
 - 5. t_{AS} is measured from the address valid to the beginning of write.
 - 6. t_{WR} is measured from the earlier of WE# or CS# going high to the end of write cycle.
 - 7. During this period, I/O pins are in the output state so that the input signals of the opposite phase to the outputs must not be applied.
 - 8. If the CS# low transition occurs simultaneously with the WE# low transition or after the WE# transition, the output remain in a high impedance state.
 - 9. Dout is the same phase of the write data of this write cycle.
 - 10. Dout is the read data of next address.
 - 11. If CS# is low during this period, I/O pins are in the output state. Therefore, the input signals of the opposite phase to the outputs must not be applied to them.
 - 12. In the write cycle with OE# low fixed, t_{WP} must satisfy the following equation to avoid a problem of data bus contention. $t_{WP} \ge t_{DW} \min + t_{WHZ} \max$

Timing Waveform

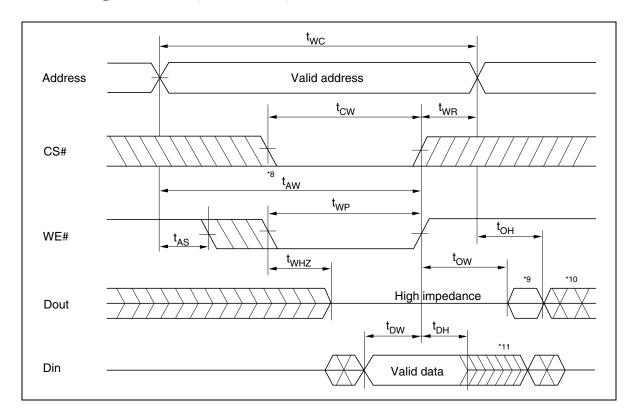
Read Timing Waveform (WE# = V_{IH})



Write Timing Waveform (1) (OE# Clock)



Write Timing Waveform (2) (OE# Low Fixed)



Low V_{CC} Data Retention Characteristics

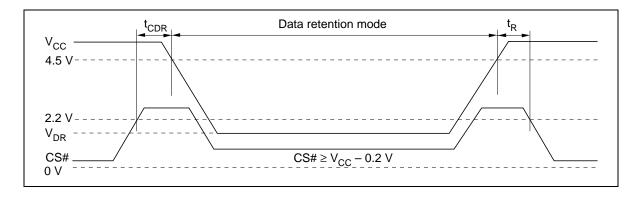
 $(Ta = -20 \text{ to } +70^{\circ}\text{C})$

| Parameter | | | Symbol | Min | Тур | Max | Unit | Test conditions*3 |
|--------------------------------------|-------------|------------------|-------------------|-----|-------|-----|------------------------|--|
| V _{CC} for data | a retention | | V_{DR} | 2 | | _ | V | $CS\# \geq V_{CC} - 0.2 \text{ V, Vin} \geq 0 \text{ V}$ |
| Data | -5SC | to +70°C | I _{CCDR} | _ | | 8 | μΑ | V_{CC} = 3.0 V, $Vin \ge 0 V$ |
| retention current | | to +40°C | I _{CCDR} | _ | 1.0*2 | 3 | μΑ | CS# ≥ V _{CC} – 0.2 V |
| odironi | | to +25°C | I _{CCDR} | _ | 0.8*1 | 3 | μΑ | |
| | -7LC | to +70°C | I _{CCDR} | _ | | 16 | μΑ | |
| | | to +40°C | I _{CCDR} | _ | 1.0*2 | 10 | μΑ | • |
| | | to +25°C | I _{CCDR} | _ | 0.8*1 | 10 | μΑ | |
| Chip deselect to data retention time | | t _{CDR} | 0 | | _ | ns | See retention waveform | |
| Operation recovery time | | t _R | t _{RC} * | '— | _ | ns | - | |

Notes: 1. Typical values are at $V_{CC} = 3.0 \text{ V}$, $Ta = +25^{\circ}\text{C}$ and specified loading, and not guaranteed.

- 2. Typical values are at $V_{CC} = 3.0 \text{ V}$, $Ta = +40^{\circ}\text{C}$ and specified loading, and not guaranteed.
- 3. CS# controls address buffer, WE# buffer, OE# buffer, and Din buffer. In data retention mode, Vin levels (address, WE#, OE#, I/O) can be in the high impedance state.
- 4. t_{RC} = read cycle time.

$Low~V_{CC}~Data~Retention~Timing~Waveform~(CS\#~Controlled)$



Revision History

R1LP0408C-C Series Data Sheet

| Rev. | Date | Conte | Contents of Modification | | | | | | |
|------|-------------|-------|--|--|--|--|--|--|--|
| | | Page | Description | | | | | | |
| 1.00 | Aug.01.2003 | _ | Initial issue | | | | | | |
| 2.00 | May.26.2004 | 6 | DC characteristics -5SC and -7LC items' description are divided. | | | | | | |
| | | 12 | Low V _{CC} Data Retention Characteristics –5SC and –7LC items' description are divided. | | | | | | |
| | | 12 | Low V _{CC} Data Retention Timing Waveform 2.4 V to 2.2 V | | | | | | |

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